

### SW10N80K2-VB Datasheet

N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	800				
R <sub>DS(on)</sub> typ. (Ω) at 25 °C	$V_{GS} = 10 V$	0.50			
Q <sub>g</sub> max. (nC)	88				
Q <sub>gs</sub> (nC)	9				
Q <sub>gd</sub> (nC)	16				
Configuration	Single				



- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

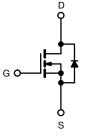


#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial
  - Welding
  - Induction heating
  - Motor drives
  - Battery chargers
  - Renewable energy
  - Solar (PV inverters)

(ТО-	252)

DPAK



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C, unless otherwise noted) PARAMETER SYMBOL LIMIT UNIT Drain-source voltage V<sub>DS</sub> 800 ٧ Gate-source voltage ± 30  $V_{GS}$ T<sub>C</sub> = 25 °C 9.0 Continuous drain current (T<sub>J</sub> = 150 °C) V<sub>GS</sub> at 10 V  $I_D$  $T_{\rm C} = 100 \,{}^{\circ}{\rm C}$ 6.8 А Pulsed drain current a 30  $I_{DM}$ Linear derating factor 1.4 W/°C Single pulse avalanche energy b E<sub>AS</sub> 226 mJ Maximum power dissipation 149 W  $P_D$ Operating junction and storage temperature range -55 to +150 °C T<sub>J</sub>, T<sub>stq</sub> T<sub>.1</sub> = 125 °C 70 Drain-source voltage slope dV/dt V/ns Reverse diode dV/dt d 4.3 Soldering recommendations (peak temperature) <sup>c</sup> For 10 s 300 °C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature

b.  $V_{DD}$  = 140 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_g$  = 25  $\Omega,$   $I_{AS}$  = 4.0 A

c. 1.6 mm from case

d.  $I_{SD} \leq I_D, \, dl/dt$  = 100 A/µs, starting  $T_J$  = 25  $^\circ C$ 

## SW10N80K2-VB



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum junction-to-ambient	R <sub>thJA</sub>	-	62	°C/W		
Maximum junction-to-case (drain)	R <sub>thJC</sub>	-	1.6	0/1		

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		•					
Drain-source breakdown voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$		800	-	-	V
V <sub>DS</sub> temperature coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	1.1	-	V/°C
Gate-source threshold voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$		-	4	V
Gate-source leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 V$		-	-	± 100	nA
		, v	V <sub>GS</sub> = ± 30 V		-	± 1	μA
		V <sub>DS</sub> =	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V		-	1	μA
Zero gate voltage drain current	IDSS	V <sub>DS</sub> = 640 V	$V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$		-	10	
Drain-source on-state resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I <sub>D</sub> = 5.5 A	-	0.5	-	Ω
Forward transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 5.5 A		-	4.5	-	S
Dynamic		•			•	•	
Input capacitance	C <sub>iss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ f = 1 MHz		-	1670	-	pF
Output capacitance	C <sub>oss</sub>			-	68	-	
Reverse transfer capacitance	C <sub>rss</sub>			-	9	-	
Effective output capacitance, energy related <sup>a</sup>	C <sub>o(er)</sub>	$V_{DS}$ = 0 V to 480 V, $V_{GS}$ = 0 V		-	43	-	
Effective output capacitance, time related <sup>b</sup>	C <sub>o(tr)</sub>			-	212	-	
Total gate charge	Qg			-	44	88	
Gate-source charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 4.5 \text{ A}, V_{DS} = 480 \text{ V}$		9	-	nC
Gate-drain charge	Q <sub>gd</sub>			-	16	-	1
Turn-on delay time	t <sub>d(on)</sub>				18	36	ns
Rise time	t <sub>r</sub>	$\label{eq:VDD} \begin{array}{l} V_{\text{DD}} = 480 \; \text{V}, \; I_{\text{D}} = 4.5 \; \text{A}, \\ V_{\text{GS}} = 10 \; \text{V}, \; R_{\text{g}} = 9.1 \; \Omega \end{array}$		-	15	30	
Turn-off delay time	t <sub>d(off)</sub>			-	55	110	
Fall time	t <sub>f</sub>			-	18	36	
Gate input resistance	Rg	f = 1 MHz, open drain		0.4	0.9	1.8	Ω
Drain-Source Body Diode Characteristic	s	•			•	•	
Continuous source-drain diode current	۱ <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	12	A
Pulsed diode forward current	I <sub>SM</sub>			-	-	32	
Diode forward voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 5.5 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse recovery time	t <sub>rr</sub>	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 5.5 \text{ A},$ di/dt = 100 A/µs, V <sub>R</sub> = 25 V		-	345	690	ns
Reverse recovery charge	Q <sub>rr</sub>			-	4.2	8.4	μC
Reverse recovery current	I <sub>RRM</sub>			-	21	-	A

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ 



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

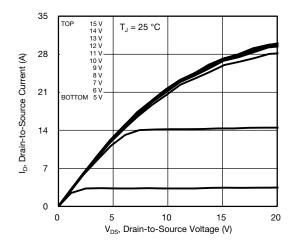


Fig. 1 - Typical Output Characteristics

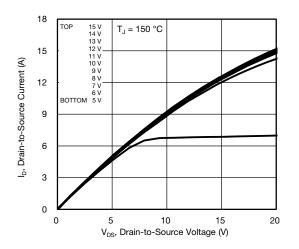


Fig. 2 - Typical Output Characteristics

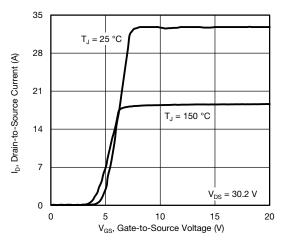


Fig. 3 - Typical Transfer Characteristics

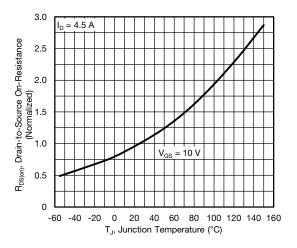


Fig. 4 - Normalized On-Resistance vs. Temperature

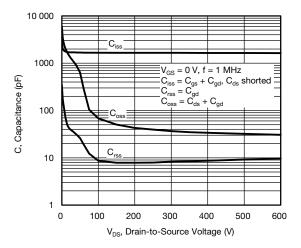


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

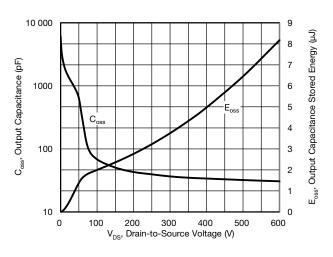


Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 



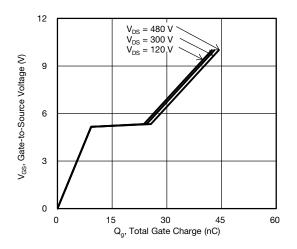


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

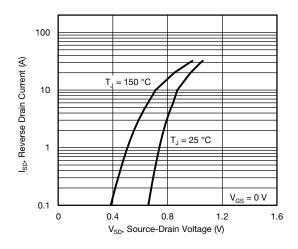


Fig. 8 - Typical Source-Drain Diode Forward Voltage

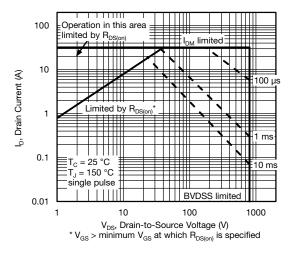


Fig. 9 - Maximum Safe Operating Area

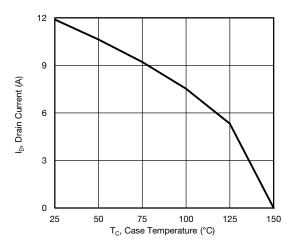


Fig. 10 - Maximum Drain Current vs. Case Temperature

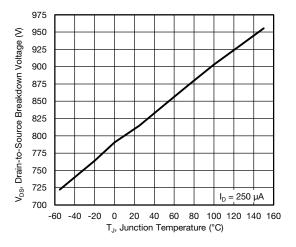
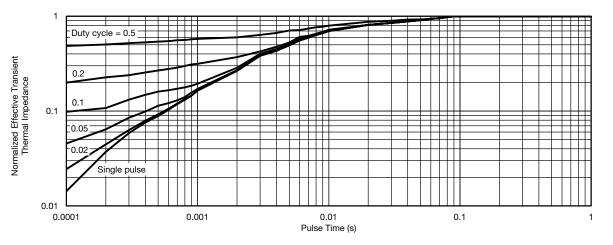


Fig. 11 - Temperature vs. Drain-to-Source Voltage





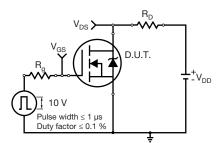


Fig. 13 - Switching Time Test Circuit

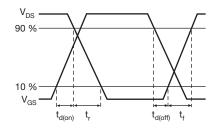


Fig. 14 - Switching Time Waveforms

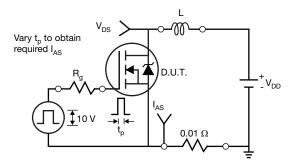


Fig. 15 - Unclamped Inductive Test Circuit

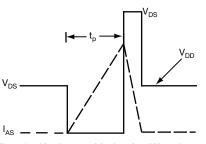


Fig. 16 - Unclamped Inductive Waveforms

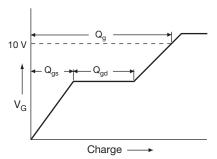


Fig. 17 - Basic Gate Charge Waveform

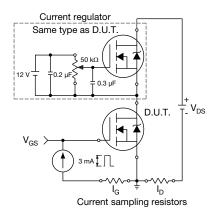


Fig. 18 - Gate Charge Test Circuit

semi

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Peak Diode Recovery dV/dt Test Circuit

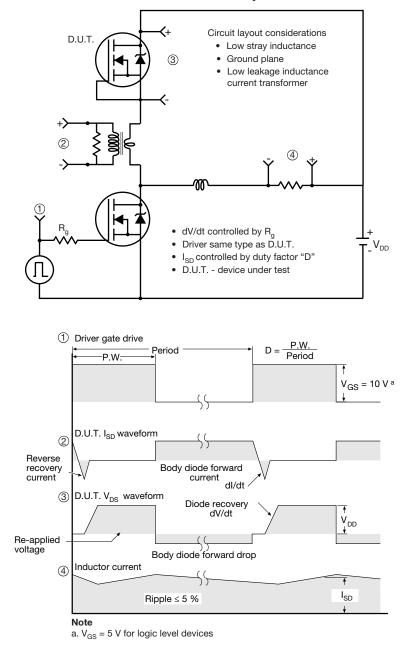


Fig. 19 - For N-Channel



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